

<b>Notice of References Cited</b>	Application/Control No. 10/524,444		Applicant(s)/Patent Under Reexamination MOCHIZUKI ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,002,834 A	12-1999	Hirabayashi et al.	386/70
	B	US-			
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	D	US-			
	E	US-			
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	N					
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#### NON-PATENT DOCUMENTS

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